IEEE HOME I SEARCH IEEE I SHOP I WEB ACCOUNT I CONTACT IEEE



Membership Publica	itions/Services Standards Conferences Careers/.	Jobs
IEEE)	RELEASE 1.7	I EEE Xplore® 1 Million Documents 1 Million Users
Help FAQ Terms IEE	E Peer Review Quick Links	» Se
Welcome to IEEE Xplores - Home - What Can I Access?	Your search matched 1 of 1034809 docum A maximum of 500 results are displayed, 1 Descending order.	
O- Log-out	Refine This Search:	
Tables of Contents	You may refine your search by editing the current search expression or enterinew one in the text box.	
O- Journals	(content <in>ab) <and> (accessibility<in>ab) <and< th=""></and<></in></and></in>	
& Magazines	Check to search within this result set	
Conference Proceedings	The second secon	
O- Standards	Results Key: JNL = Journal or Magazine CNF = Conference STD = Standard	
Search		
O- By Author O- Basic O- Advanced	Measuring the difficulty of assembly Diaz-Calderon, A.; Navin-Chandra, D.; Kho Assembly and Task Planning, 1995. Procee on, 10-11 Aug. 1995	sla, P.K.;
Member Services	Pages:87 - 93	
O- Join IEEE O- Establish IEEE Web Account	[Abstract] [PDF Full-Text (596 KB)] IEE	EE CNF
Access the IEEE Member Digital Library		

Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE — All rights reserved